

P-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}$ (Ω)	I _D (A) ^a	Q _g (Typ.)		
20	0.007 at $V_{GS} = -10 \text{ V}$	-14	6.500		
-30	0.010 at $V_{GS} = -4.5 \text{ V}$	-13	6.5nC		

SO-8

Top View

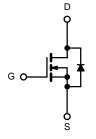
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FEATURES

- · Halogen-free
- TrenchFET® Power MOSFET
- Optimized for High-Side Synchronous Rectifier Operation
- 100 % R_g Tested
- 100 % UIS Tested

APPLICATIONS

- Notebook CPU Core
 - High-Side Switch



N-Channel MOSFET

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	-30	V		
Gate-Source Voltage		V _{GS}	± 20	v	
	T _C = 25 °C		-14		
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C		-13		
Continuous Diain Current (1) = 150 °C)	T _A = 25 °C	I _D	-13 ^{b, c}		
	T _A = 70 °C		-11.5 ^{b, c}		
Pulsed Drain Current	I _{DM}	-45	A		
Continuous Source-Drain Diode Current	T _C = 25 °C	I.	-3.8		
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	-2.1 ^{b, c}		
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	-22		
Avalanche Energy	L=0.11III	E _{AS}	24	mJ	
	T _C = 25 °C		4.0		
Maximum Daylar Dissipation	T _C = 70 °C	P _D	2.6	W	
Maximum Power Dissipation	T _A = 25 °C	rD	2.4 ^{b, c}		
	T _A = 70 °C		1.5 ^{b, c}		
Operating Junction and Storage Temperature Ra	T _J , T _{stq}	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	38	50	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	22	28	C/VV	

Notes:

- a. Base on T_C = 25 °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under Steady State conditions is 85 °C/W.



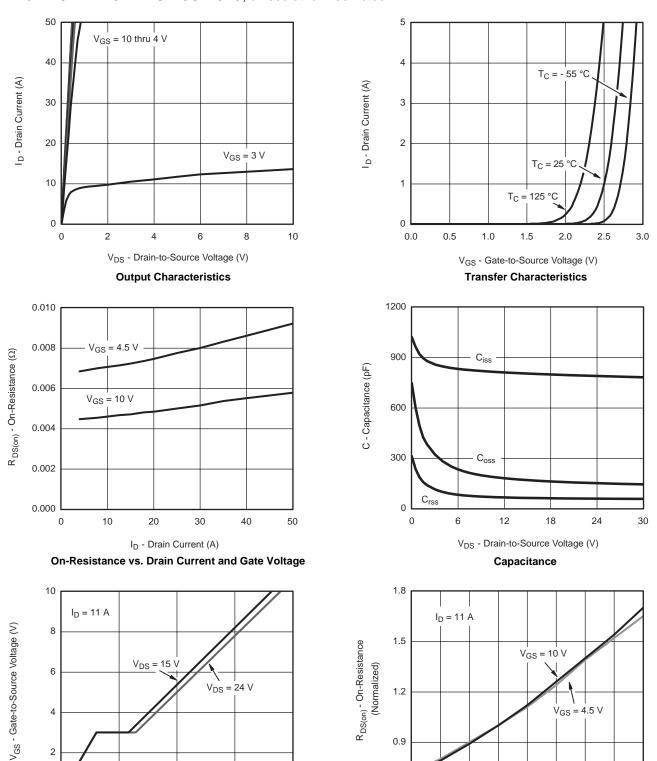
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static						<u> </u>	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	-30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J. 250A		-28		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 6			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	-1.0		-3.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
7 0 1 1/1 5 1 0 1	,	V _{DS} = -30 V, V _{GS} = 0 V			-1	^	
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 30 V, V _{GS} = 0 V, T _J = 55 °C			-10 μA		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge -5 \text{ V}, V_{GS} = -10 \text{ V}$	-45			Α	
	_	V _{GS} = -10 V, I _D = -11 A	0.007				
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = -4.5 V, I _D = -10 A		0.010		Ω	
Forward Transconductance ^a	<u> </u>			52		S	
Dynamic ^b	l l						
Input Capacitance	C _{iss}			5950			
Output Capacitance	C _{oss}	$V_{DS} = -15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		195		pF	
Reverse Transfer Capacitance	C _{rss}	30		73			
Total Gate Charge		V _{DS} = -15 V, V _{GS} = -10 V, I _D = -11 A		15	23	nC	
	Q _g	Q _g		6.8	10.2		
Gate-Source Charge	Q _{gs}	$V_{DS} = -15 \text{ V}, V_{GS} = -5 \text{ V}, I_{D} = -11 \text{ A}$		2.5			
Gate-Drain Charge	Q_{gd}			2.3			
Gate Resistance	R_g	f = 1 MHz	0.36	1.8	3.6	Ω	
Turn-On Delay Time	t _{d(on)}			16	24		
Rise Time	t _r	V_{DD} = -15 V, R_L = 1.4 Ω		12	18		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong -9 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_g = 1$		16	24		
Fall Time	t _f	Ω		10	20	200	
Turn-On Delay Time	t _{d(on)}			8	16	ns -	
Rise Time	t _r	V_{DD} = -15 V, R_L = 1.4 Ω		10	20		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong -9 \text{ A, } V_{GEN} = -10 \text{ V, } R_g = 1$		16	24		
Fall Time	t _f	Ω		8	15		
Drain-Source Body Diode Characteris	ics						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			-45	Α	
Pulse Diode Forward Current ^a	I _{SM}				-50		
Body Diode Voltage	V_{SD}	I _S = -9 A		-0.8	-1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			15	30	ns	
ody Diode Reverse Recovery Charge Q _{rr}		I _F = 9 A, dl/dt = 100 A/μs, T _J = 25 °C		6	12	nC	
Reverse Recovery Fall Time	t _a	t _a		8		20	
Reverse Recovery Rise Time	t _b			7		ns	

Notes

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.





0.9

0.6

- 50

- 25

0

25

50

T_J - Junction Temperature (°C)

On-Resistance vs. Junction Temperature

75

100

125

150

16

服务热线:400-655-8788

2

0

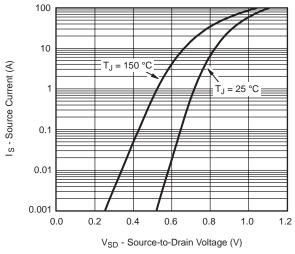
0

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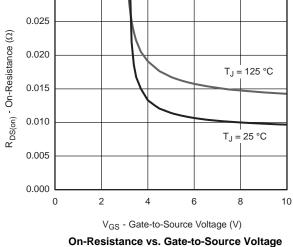
Q_q - Total Gate Charge (nC)

Gate Charge

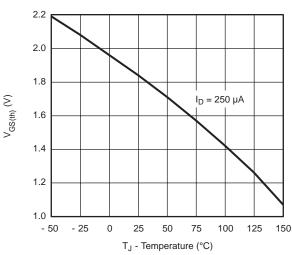




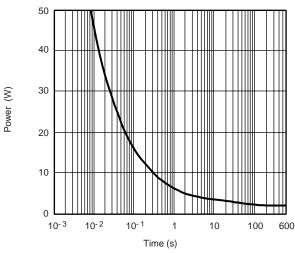
Source-Drain Diode Forward Voltage



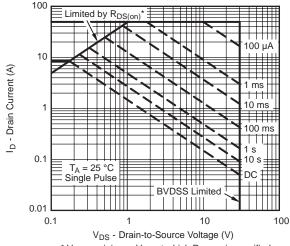
0.030



Threshold Voltage



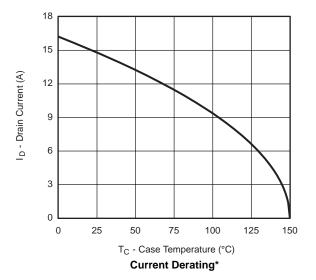
Single Pulse Power, Junction-to-Ambient

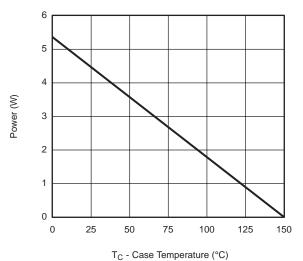


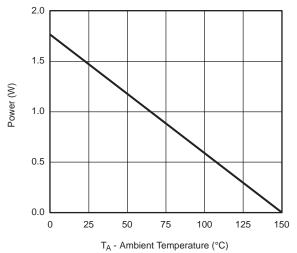
* $V_{GS} > \mbox{minimum } V_{GS}$ at which $R_{DS(on)}$ is specified

Safe Operating Area, Junction-to-Ambient







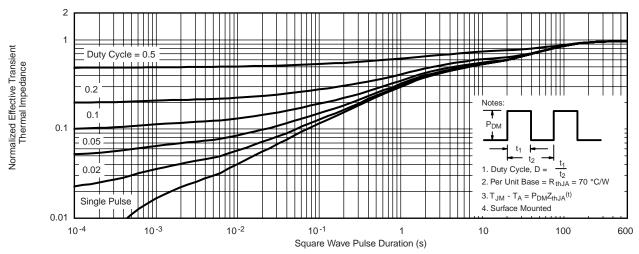


Power Derating, Junction-to-Foot

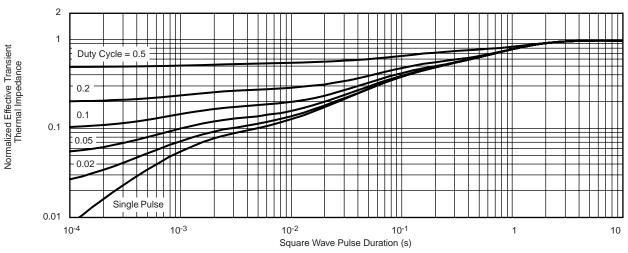
Power Derating, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





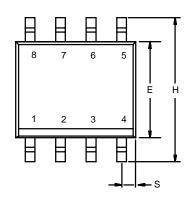
Normalized Thermal Transient Impedance, Junction-to-Ambient

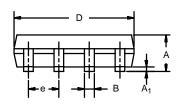


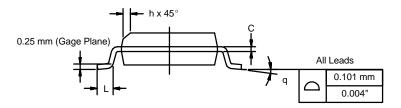
Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEADJEDEC Part Number: MS-012







	MILLIM	IETERS	INC	HES	
DIM	Min	Max	Min	Max	
Α	1.35	1.75	0.053	0.069	
A ₁	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
E	3.80	4.00	0.150	0.157	
е	1.27 BSC		0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
FCN: C-06527-Rev I 11-Sen-06					

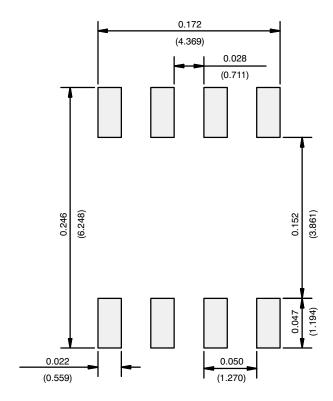
ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498

8



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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